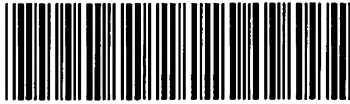


Search Notes

Application/Control No.

10/774,594

Examiner

Mark A. X Radtke

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2165

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted Primary Examiner Sam Rimell regarding 132 affidavits	4/11/2007	MAXR